

ON Semiconductor®

# FGH75T65UPD-F085 650V, 75A Field Stop Trench IGBT

### **Features**

- Maximum Junction Temperature: T<sub>J</sub> = 175°C
- · Positive Temperaure Co-efficient for easy parallel operating
- · High current capability
- Low saturation voltage:  $V_{CE(sat)} = 1.65V(Typ.) @ I_C = 75A$
- · High input impedance
- Tightened Parameter Distribution
- RoHS compliant
- Qualified to Automotive Requirements of AEC-Q101

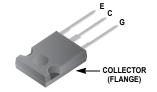


### **General Description**

Using Novel Field Stop Trench IGBT Technology, ON Semiconductor's new series of Field Stop Trench IGBTs offer the optimum perfor-mance for Automotive chargers, Solar Inverter, UPS and Digital Power Generator where low conduction and switching losses are essential.

### **Applications**

- Automotive chargers, Converters, High Voltage Auxiliaries
- · Solar Inverters, UPS, Digital Power Generator





## **Absolute Maximum Ratings**

| Symbol              | Description  |                          | Ratings     | Units |  |
|---------------------|--|--------------------------|-------------|-------|--|
| V <sub>CES</sub>    | Collector to Emitter Voltage   |                          | 650         | V     |  |
| V <sub>GES</sub>    | Gate to Emitter Voltage  |                          | ± 20        | V     |  |
| I <sub>C</sub>      | Collector Current  | @ T <sub>C</sub> = 25°C  | 150         | А     |  |
|                     | Collector Current  | @ T <sub>C</sub> = 100°C | 75          | А     |  |
| I <sub>CM (1)</sub> | Pulsed Collector Current   |                          | 225         | А     |  |
| I <sub>F</sub>      | Diode Forward Current  | @ T <sub>C</sub> = 25°C  | 75          | А     |  |
|                     | Diode Forward Current  | @ T <sub>C</sub> = 100°C | 50          | А     |  |
| I <sub>FM(1)</sub>  | Pulsed Diode Maximum Forward Current                                       |                          | 225         | А     |  |
| $P_{D}$             | Maximum Power Dissipation  | @ T <sub>C</sub> = 25°C  | 375         | W     |  |
|                     | Maximum Power Dissipation  | @ T <sub>C</sub> = 100°C | 187         | W     |  |
| SCWT                | Short Circuit Withstand Time   | $@ T_C = 25^{\circ}C$    | 5           | us    |  |
| T <sub>J</sub>      | Operating Junction Temperature   |                          | -55 to +175 | °C    |  |
| T <sub>stg</sub>    | Storage Temperature Range  |                          | -55 to +175 | °C    |  |
| T <sub>L</sub>      | Maximum Lead Temp. for soldering<br>Purposes, 1/8" from case for 5 seconds |                          | 300         | °C    |  |

### **Thermal Characteristics**

| Symbol                      | Parameter                            | Ratings | Units |  |
|-----------------------------|--------------------------------------|---------|-------|--|
| $R_{\theta JC}(IGBT)_{(2)}$ | Thermal Resistance, Junction to Case | 0.4     | °C/W  |  |
| $R_{\theta JC}(Diode)$      | Thermal Resistance, Junction to Case | 0.86    | °C/W  |  |

| Symbol         | Parameter  | Тур. | Units |  |
|----------------|--|------|-------|--|
| $R_{	heta JA}$ | Thermal Resistance, Junction to Ambient (PCB Mount)(2) | 40   | °C/W  |  |

## **Package Marking and Ordering Information**

| <b>Device Marking</b> | Device           | Package | Packing Type | Qty per Tube |
|-----------------------|------------------|---------|--------------|--------------|
| FGH75T65UPD           | FGH75T65UPD-F085 | TO-247  | Tube         | 30ea         |

| Symbol                                 | Parameter                                    | Test Conditions  | Min. | Тур. | Max. | Units |
|--|--|--|------|------|------|-------|
| Off Charac                             | teristics                                    |  |      |      |      |       |
| BV <sub>CES</sub>                      | Collector to Emitter Breakdown Voltage       | $V_{GE} = 0V$ , $I_C = 1mA$  | 650  | -    | -    | V     |
| $\frac{\Delta BV_{CES}}{\Delta T_{J}}$ | Temperature Coefficient of Breakdown Voltage | V <sub>GE</sub> = 0V, I <sub>C</sub> = 1mA                             | -    | 0.65 | -    | V/°C  |
| I <sub>CES</sub>                       | Collector Cut-Off Current                    | $V_{CE} = V_{CES}, V_{GE} = 0V$  | -    | -    | 250  |       |
|  |  | I <sub>CES</sub> at 80%*B <sub>VCES</sub> , 175°C                      | -    | -    | 3600 | μΑ    |
| I <sub>GES</sub>                       | G-E Leakage Current                          | $V_{GE} = V_{GES}, V_{CE} = 0V$  | -    | -    | ±400 | nA    |
| On Charac                              | teristics                                    |  |      |      |      |       |
| V <sub>GE(th)</sub>                    | G-E Threshold Voltage                        | I <sub>C</sub> = 75mA, V <sub>CE</sub> = V <sub>GE</sub>               | 4.0  | 6.0  | 7.5  | V     |
| OL(ui)                                 | , , ,  | $I_C = 75A, V_{GE} = 15V$  | -    | 1.69 | 2.3  | V     |
| $V_{\text{CE(sat)}}$                   | Collector to Emitter Saturation Voltage      | I <sub>C</sub> = 75A, V <sub>GE</sub> = 15V,<br>T <sub>C</sub> = 175°C | -    | 2.21 | -    | V     |
| Dynamic C                              | Characteristics                              |  |      |      |      |       |
| C <sub>ies</sub>                       | Input Capacitance                            |  | _    | 5665 | _    | pF    |
| C <sub>oes</sub>                       | Output Capacitance                           | $V_{CE} = 30V, V_{GE} = 0V,$   | _    | 205  | -    | pF    |
| C <sub>res</sub>                       | Reverse Transfer Capacitance                 | f = 1MHz   | _    | 100  | -    | pF    |
| Switching                              | Characteristics                              |  | 1    | •    | •    |       |
| t <sub>d(on)</sub>                     | Turn-On Delay Time                           |  | -    | 32   | 48   | ns    |
| t <sub>r</sub>                         | Rise Time                                    |  | -    | 43   | 71   | ns    |
| t <sub>d(off)</sub>                    | Turn-Off Delay Time                          | $V_{CC} = 400V, I_{C} = 75A,$  | -    | 166  | 216  | ns    |
| t <sub>f</sub>                         | Fall Time                                    | $R_G = 3\Omega$ , $V_{GE} = 15V$ ,                                     | -    | 24   | 33   | ns    |
| E <sub>on</sub>                        | Turn-On Switching Loss                       | Inductive Load, T <sub>C</sub> = 25°C                                  | -    | 2.85 | 4.80 | mJ    |
| E <sub>off</sub>                       | Turn-Off Switching Loss                      |  | -    | 1.20 | 1.60 | mJ    |
| E <sub>ts</sub>                        | Total Switching Loss                         |  | -    | 4.05 | 5.3  | mJ    |
| t <sub>d(on)</sub>                     | Turn-On Delay Time                           |  | -    | 30   | -    | ns    |
| t <sub>r</sub>                         | Rise Time                                    |  | -    | 57   | -    | ns    |
| t <sub>d(off)</sub>                    | Turn-Off Delay Time                          | $V_{CC} = 400V, I_{C} = 75A,$  | -    | 176  | -    | ns    |
| t <sub>f</sub>                         | Fall Time                                    | $R_G = 3\Omega$ , $V_{GE} = 15V$ ,                                     | -    | 21   | -    | ns    |
| E <sub>on</sub>                        | Turn-On Switching Loss                       | Inductive Load, T <sub>C</sub> = 175°C                                 | -    | 4.45 | -    | mJ    |
| E <sub>off</sub>                       | Turn-Off Switching Loss                      |  | -    | 1.60 | -    | mJ    |
| E <sub>ts</sub>                        | Total Switching Loss                         |  | -    | 6.05 | -    | mJ    |
| Tsc                                    | Short Circuit Withstand Time                 | $V_{\rm GE}$ = 15V, $V_{\rm CC}$ $\leq$ 400V, Rg = 10 $\Omega$         | 5    | -    | -    | us    |

#### Notes:

2:Rthjc for TO-247: according to Mil standard 883-1012 test method. Rthja for TO-247: according to JESD51-2, test method environmental condition and JESD51-10, test boards for through hole perimeter leaded package thermal measurements. JESD51-3: Low Effective Thermal Conductivity Test Board for Leaded Surface Mount Package.

<sup>1:</sup>Repetitive rating: Pulse width limited by max junction temperature.

## **Electrical Characteristics of the IGBT** (Continued)

| Symbol          | Parameter                | Test Conditions  | Min. | Тур. | Max | Units |
|-----------------|--------------------------|--|------|------|-----|-------|
| $Q_g$           | Total Gate Charge        | V <sub>CE</sub> = 400V, I <sub>C</sub> = 75A,<br>V <sub>GE</sub> = 15V | -    | 385  | 578 | nC    |
| Q <sub>ge</sub> | Gate to Emitter Charge   |  | -    | 45   | 68  | nC    |
| $Q_{gc}$        | Gate to Collector Charge |  | -    | 210  | 315 | nC    |

## Electrical Characteristics of the Diode $T_C = 25^{\circ}C$ unless otherwise noted

| Symbol           | Parameter  | Test Conditions                                    |                                  | Min. | Тур. | Max | Units |
|------------------|--|--|----------------------------------|------|------|-----|-------|
| V <sub>FM</sub>  | Diode Forward Voltage  | I <sub>F</sub> = 50A                               | $T_{\rm C} = 25^{\rm o}{\rm C}$  | -    | 2.1  | 2.6 | . v   |
|                  |  |  | $T_{\rm C} = 175^{\rm o}{\rm C}$ | -    | 1.7  | -   |       |
| E <sub>rec</sub> | Reverse Recovery Energy  |  | $T_{\rm C} = 175^{\rm o}{\rm C}$ | -    | 40   | -   | uJ    |
| t                | t <sub>rr</sub> Diode Reverse Recovery Time  | I <sub>F</sub> =50A, dI <sub>F</sub> /dt = 200A/μs | $T_{\rm C} = 25^{\rm o}{\rm C}$  | =    | 43   | 85  | ns    |
| ۲r               |  |  | $T_{\rm C} = 175^{\rm o}{\rm C}$ | -    | 162  | -   | 110   |
| Q <sub>rr</sub>  | Diode Reverse Recovery Charge  |  | $T_{\rm C} = 25^{\rm o}{\rm C}$  | =    | 83   | 170 | nC    |
| ~II              | 2.533 No. 3. 3. No. 3 No |  | $T_{\rm C} = 175^{\rm o}{\rm C}$ | -    | 805  | ı   | 0     |

**Figure 1. Typical Output Characteristics** 

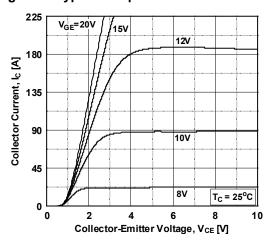


Figure 3. Typical Saturation Voltage Characteristics

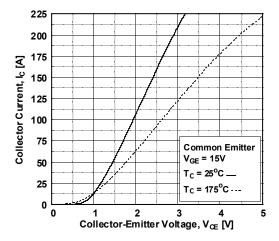


Figure 5. Saturation Voltage vs. Case
Temperature at Variant Current Level

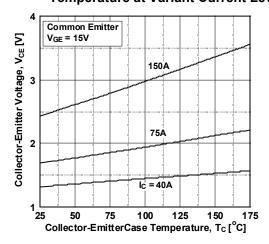
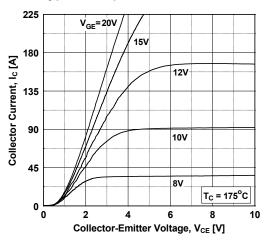


Figure 2. Typical Output Characteristics



**Figure 4. Transfer Characteristics** 

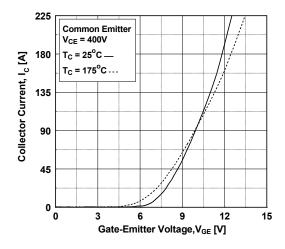


Figure 6. Saturation Voltage vs.  $V_{GE}$ 

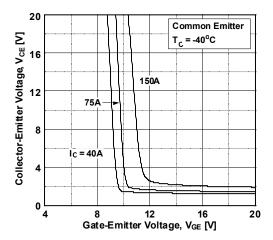


Figure 7. Saturation Voltage vs. V<sub>GE</sub>

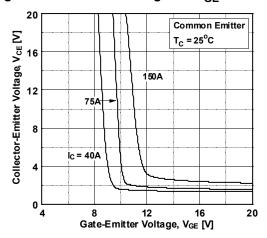


Figure 9. Capacitance Characteristics

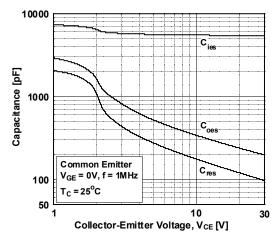


Figure 11. SOA Characteristics

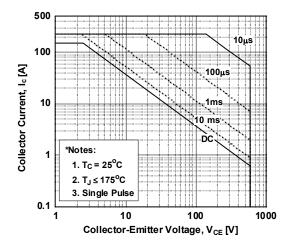


Figure 8. Saturation Voltage vs. V<sub>GE</sub>

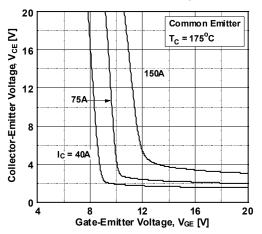


Figure 10. Gate charge Characteristics

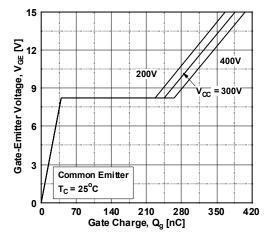


Figure 12. Turn-on Characteristics vs.
Gate Resistance

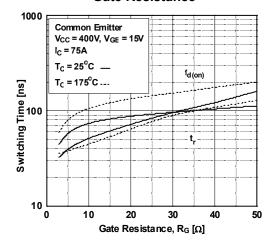


Figure 13. Turn-off Characteristics vs. Gate Resistance

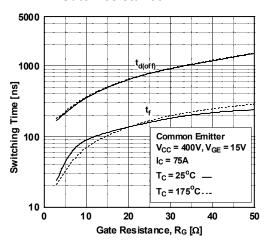


Figure 15. Turn-off Characteristics vs. Collector Current

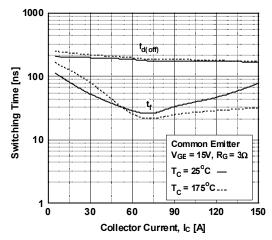


Figure 17. Switching Loss vs. Collector Current

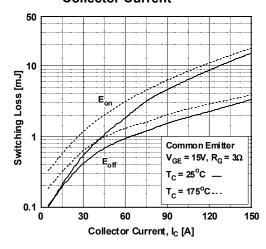


Figure 14. Turn-on Characteristics vs.
Collector Current

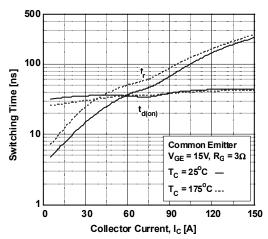


Figure 16. Switching Loss vs.
Gate Resistance

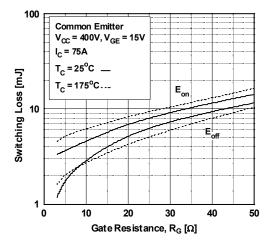


Figure 18. Turn off Switching SOA Characteristics

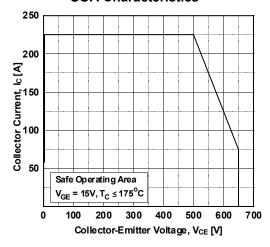


Figure 19. Current Derating

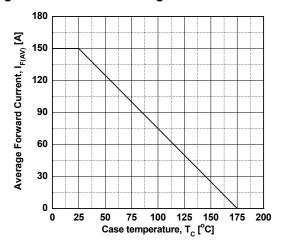


Figure 21. Forward Characteristics

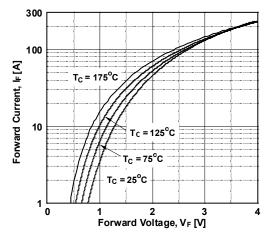


Figure 23. Stored Charge

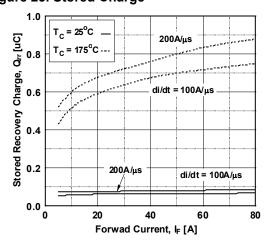


Figure 20. Load Current Vs. Frequence

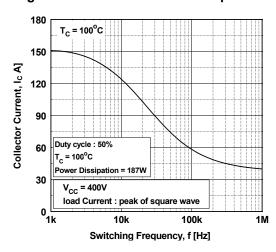


Figure 22. Reverse Recovery Current

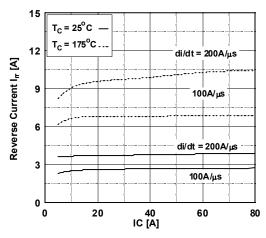


Figure 24. Reverse Recovery Time

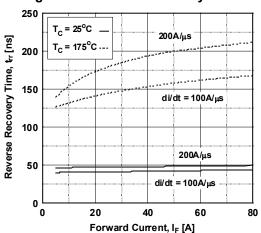


Figure 25. Transient Thermal Impedance of IGBT

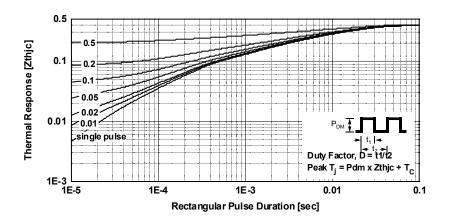
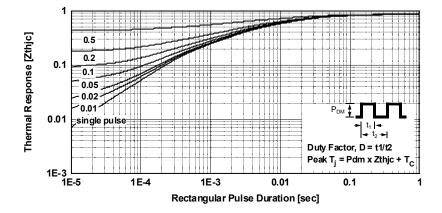
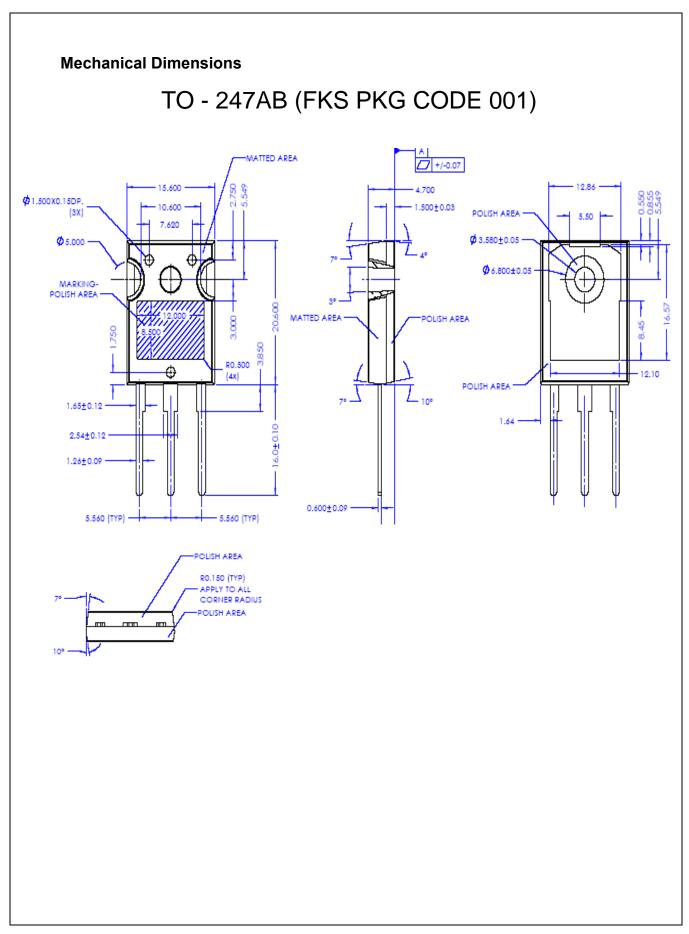


Figure 26.Transient Thermal Impedance of Diode





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